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Fast surface metrology using wavelength scanning and dispersive white light interferometry

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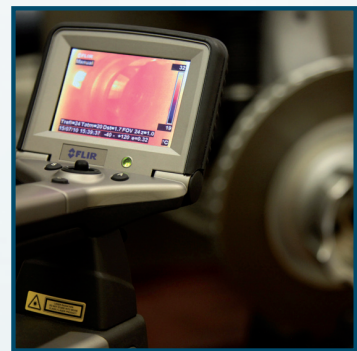
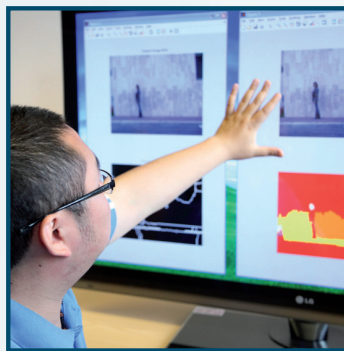
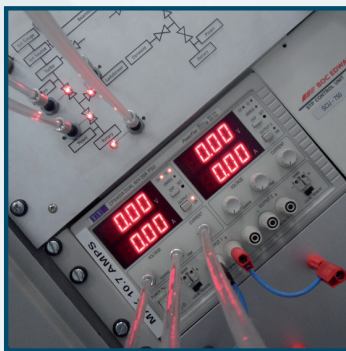


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